

Notice of References Cited	Application/Control No. 10/613,922	Applicant(s)/Patent Under Reexamination UTTERBERG, DAVID S.	
	Examiner Mark K Han	Art Unit 3763	Page 1 of 1

U.S. PATENT DOCUMENTS

* <i>mark</i>		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,188,620 A	02-1993	Jepson et al.	604/534
	B	US-			
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	K	US-			
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	A	US-5,501,426	03-1996	Atkinson et al.	251/149.1
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